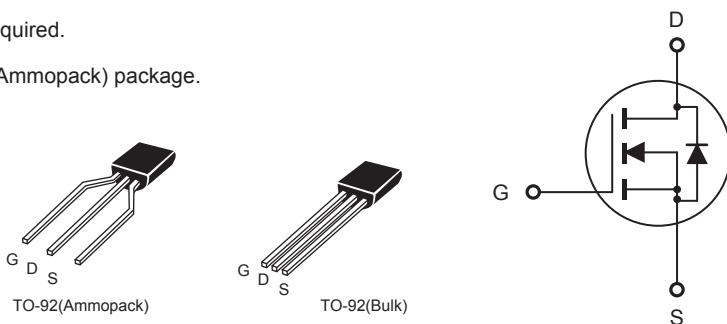


## N-Channel Enhancement Mode Field Effect Transistor

### FEATURES

- 650V, 0.3A,  $R_{DS(ON)} = 15 \Omega$  @ $V_{GS} = 10V$ .
- High dense cell design for extremely low  $R_{DS(ON)}$ .
- Rugged and reliable.
- Lead free product is acquired.
- TO-92(Bulk) & TO-92(Ammopack) package.



### ABSOLUTE MAXIMUM RATINGS $T_A = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	$V_{DS}$	650	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Drain Current-Continuous	$I_D$	0.3	A
Drain Current-Pulsed <sup>a</sup>	$I_{DM}$	1.2	A
Maximum Power Dissipation	$P_D$	3.1	W
Operating and Store Temperature Range	$T_J, T_{stg}$	-55 to 150	$^\circ C$

### Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Lead <sup>b</sup>	$R_{\theta JL}$	40	$^\circ C/W$



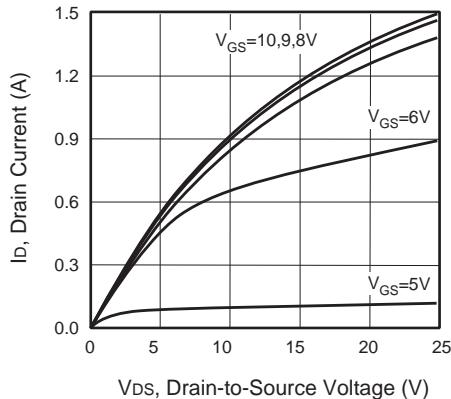
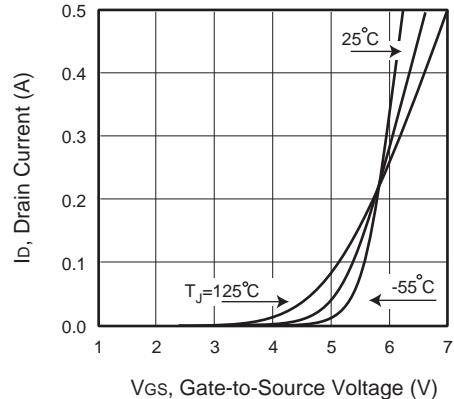
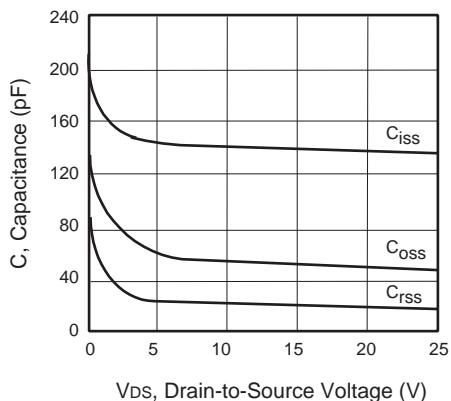
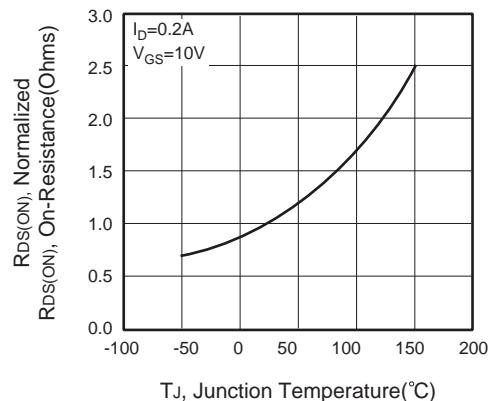
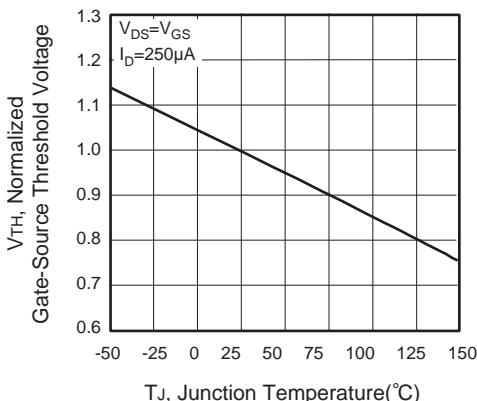
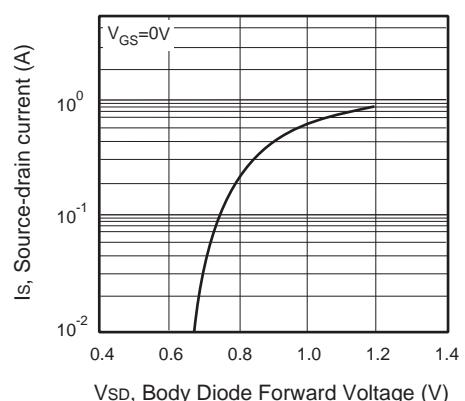
CEK01N6 □

**Electrical Characteristics**  $T_C = 25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	650			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 650\text{V}, V_{\text{GS}} = 0\text{V}$		1		$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 30\text{V}, V_{\text{DS}} = 0\text{V}$		100		nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -30\text{V}, V_{\text{DS}} = 0\text{V}$		-100		nA
<b>On Characteristics</b>						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	2		4	V
Static Drain-Source On-Resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}} = 10\text{V}, I_D = 0.2\text{A}$		12	15	$\Omega$
<b>Dynamic Characteristics</b> <sup>c</sup>						
Forward Transconductance	$g_{\text{FS}}^{\text{b}}$	$V_{\text{DS}} = 20\text{V}, I_D = 0.3\text{A}$		0.5		S
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		140		pF
Output Capacitance	$C_{\text{oss}}$			52		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			23		pF
<b>Switching Characteristics</b> <sup>c</sup>						
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}} = 300\text{V}, I_D = 0.3\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 4.7\Omega$		17	34	ns
Turn-On Rise Time	$t_r$			11	22	ns
Turn-Off Delay Time	$t_{\text{d(off)}}$			28	56	ns
Turn-Off Fall Time	$t_f$			30	60	ns
Total Gate Charge	$Q_g$	$V_{\text{DS}} = 480\text{V}, I_D = 0.3\text{A}, V_{\text{GS}} = 10\text{V}$		9.9	12.8	nC
Gate-Source Charge	$Q_{\text{gs}}$			1		nC
Gate-Drain Charge	$Q_{\text{gd}}$			7.3		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current	$I_S$				0.3	A
Drain-Source Diode Forward Voltage <sup>b</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_S = 0.2\text{A}$			1.6	V

## Notes :

- a.Repetitive Rating : Pulse width limited by maximum junction temperature.  
 b.Pulse Test : Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .  
 c.Guaranteed by design, not subject to production testing.□

**Figure 1. Output Characteristics****Figure 2. Transfer Characteristics****Figure 3. Capacitance****Figure 4. On-Resistance Variation with Temperature****Figure 5. Gate Threshold Variation with Temperature****Figure 6. Body Diode Forward Voltage Variation with Source Current**

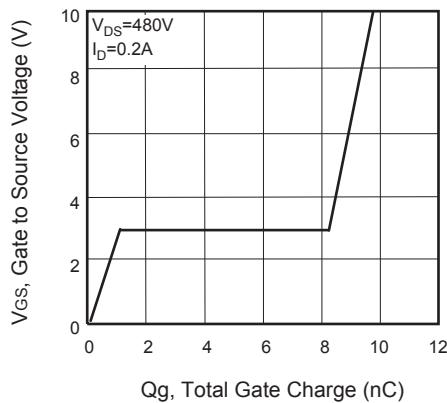


Figure 7. Gate Charge

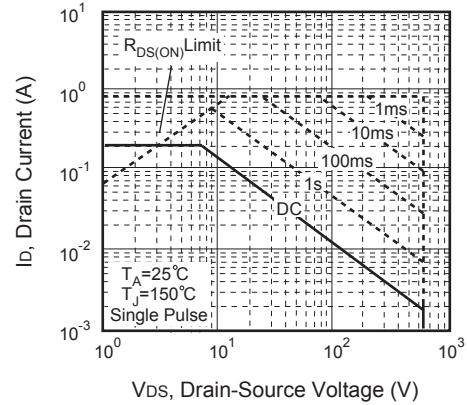


Figure 8. Maximum Safe Operating Area

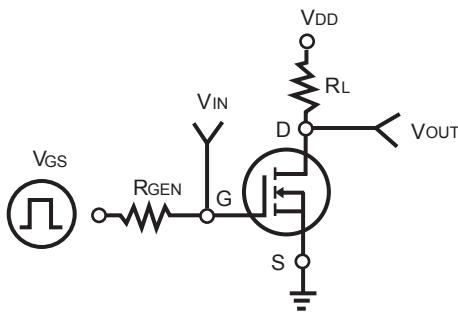


Figure 9. Switching Test Circuit

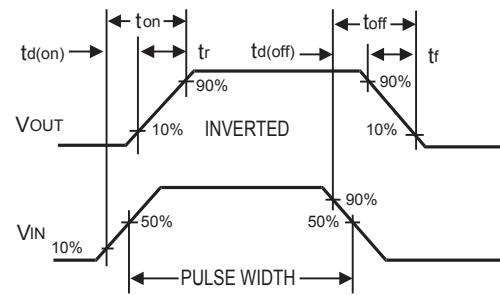


Figure 10. Switching Waveforms

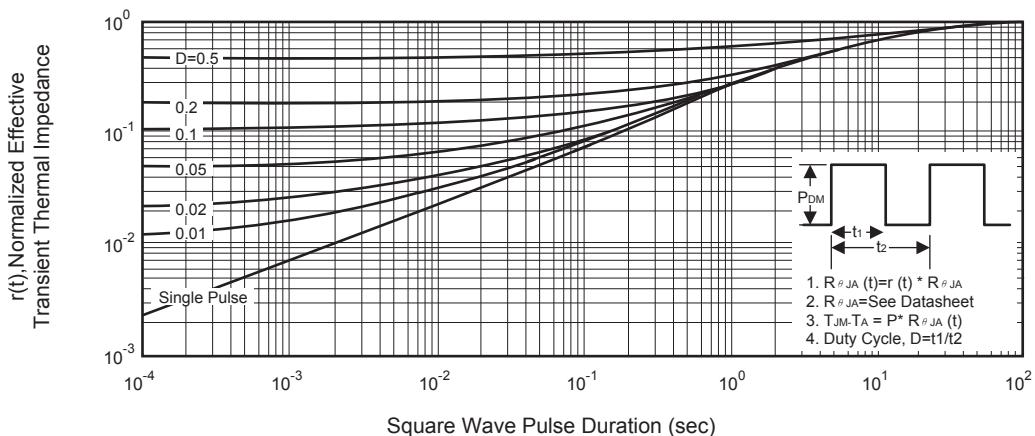


Figure 11. Normalized Thermal Transient Impedance Curve